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# StratEdge, J microTechnology, and Accel-RF Host MMIC Packaging, Testing and Reliability Seminar at MTT-S

**San Diego, Calif – April 25, 2006 –** StratEdge, leader in the design and production of semiconductor packages for microwave, millimeter wave, and high speed digital devices, along with J microTechnology and Accel-RF, announced they will be hosting a seminar on monolithic microwave integrated circuit (MMIC) packaging, testing, and reliability on June 14, 2006 at Moscone Center in San Francisco in conjunction with the MTT-S trade show.

The seminar will feature three experts in the fields of compound semiconductors, packages for high frequency devices, and reliability testing. Jerry Carter, senior applications engineer for StratEdge, will discuss the latest package technologies and assembly techniques for microwave and millimeter wave MMICs. Jerry Schappacher, an expert on probe technology, will discuss testing methods and probe stations for testing bare and packaged MMICs up through 65GHz. Roland Shaw, president of Accel-RF, will discuss accelerated life-test/burn-in test systems for compound semiconductor devices which are used in the implementation of broadband wireless infrastructures and networks.

"We are excited to be able to hold this seminar during MTT-S, which is one of the preeminent trade shows for microwave theory and techniques," said StratEdge president and CEO Tim Going. "We've had many questions about how to package and test MMICs. The seminar offers an opportunity for engineers to see the packages and test equipment and speak to the applications engineers to better understand how to maximize the characteristics of their own MMICs."

To attend the seminar contact Hannah Foster at 858- 560-6877, h.foster@stratedge.com.

### About Accel-RF

Accel-RF Corporation is a closely-held private corporation located in San Diego, California. The company specializes in the development, design, and production of accelerated life-test/burn-in test systems for RF semiconductor devices. These systems are turn-key integrated instruments

that provide a cost-effective and high-value proposition for manufacturers, fabless designers, testing-service providers, original equipment manufacturers, system integrators, and research and development laboratories requiring intrinsic reliability identification, process-control validation, specification standard-deviation characterization, and product qualification testing. For more information visit our website at www.accelrf.com.

### About J microTechnology

J microTechnology, Portland, Oregon, designs and manufactures test stations for testing bare and packaged MMICs up through 65GHz. Equipment options include high power microscopes, thermal chucks for low and high temperature probe testing, and low cost engineering and university probe station models designed specifically for students and individual engineers. For more information visit our website at www.jmicrotechnology.com.

### About StratEdge

StratEdge, founded in 1992, designs, manufactures, and provides test and assembly services for a complete line of high performance semiconductor packages operating from DC to 50+ GHz for the high speed digital (OC-48, OC-192, OC-768), mixed signal, broadband wireless, satellite, point-to-point/multipoint, VSAT, and test and measurement industries, as well as aerospace stripline filters. StratEdge offers ceramic, low cost hermetic SMT, and metal packages. All packages are lead-free and meet RoHS and WEEE standards. For more information contact StratEdge at 858- 560-6877, email: <u>info@stratedge.com</u>, or visit our website at www.stratedge.com.

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